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ISO/IEC

17025:2017

**ISO** 

9001:2015

#### Certificate of Analysis

Revision No.: 001 Revision Date: 03/30/2022

ISO

17034:2016

# **Certified Reference Material**

### Product ID: MBH-32X PB15 B

## **Product Description:** Copper Alloy, Phosphor-Bronze

Description and Intended Use: This Certified Reference Material is covered under the scope of accreditation to ISO 17034 by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in ISO 17025 accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods. Cartified Values listed in wt % with associated uncertainties

			Ce	ertified value	es liste	a in wt.%	with as	ssociated ui	icertain	lies			
Al	0.064	± 0.002	As	0.102	± 0.	.003	Bi	0.0002	± 0.0	001	Co	0.037	± 0.001
Cr	0.0004	± 0.0002	Fe	0.044	± 0.	002	Mg	0.023	± 0.0	01	Mn	0.0006	± 0.0002
Ni	0.145	± 0.003	Ρ	0.104	± 0.	005	Pb	0.046	± 0.0	02	S	0.0016	± 0.0003
Sb	0.020	± 0.001	Se	0.0008	± 0.	0005	Sn	2.04	± 0.0	4	Zn	0.75	± 0.01
					Indic	ative Val	ues lis	ted in ppm					
			Ag	(<10)	Cd	(10)	Cu	(96.6%)	Nb	(40)			
			0	(<20)	Si	(50)	Zr	(10)					

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N<sub>prod</sub> is the number of units produced and N<sub>min</sub> is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (U<sub>hom</sub>). Uncertainty of the material is calculated by equation 2, where H=U<sub>hom</sub>, S= Standard deviation, t= t-value at 95% CI, and n= number of observations.

$$1.N_{MIN} = \max(10, \sqrt[3]{N_{PROD}})$$

$$2.U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognised reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- LGC Standards Manchester, NH Connecticut Metallurgical, Inc. - East Hartford, CT
  - Dirats Laboratories Westfield, MA IMR Test Labs - Lansing, NY
    - SGS MSi Melrose Park II
- NSL Analytical Services Cleveland, OH Laboratory Testing, Inc. - Hatfield, PA Applied Technical Services - Marietta, GA
  - Scrooby's Laboratory Service Rynfield, South Africa • Universal Scientific Laboratory - Revesby, Australia
- Sheffield Assay Office Sheffield, UK
- EAG Laboratories Liverpool, NY
- AnchorCert Analytical Birmingham UK .
- Institute of Non-Ferrous Metals Gliwice, Poland

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. This material is individually chill cast per piece. This manner of casting can cause the formation of inhomogeneous segregates in the upper, engraved portion of the disk. Therefore, the certification information above is not applicable to within 3mm of the engraved surface. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use. Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Kimberly Halkiotis, Global Product Manager

Conditions of Sale and Supply: All CRMs & RMs sold are subject to applic

November 5, 2021 Certification Date



ISO 17034 Accredited: Reference Materials Producer Certificate # 2848.02 ISO/IEC 17025 Accredited: Chemical Testing, Certificate # 2848.01



Conditions of Sale.

#### The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Ag	AI	As	Bi	Cd	Co	Cr	Cu	Fe	Mg	Mn	Nb	Ni
1	0.0008	0.0604	0.0930		0.00001	0.0330	0.0001	95.880	0.0360	0.0190	0.0006		0.1362
2	0.0000	0.0610	0.0930		0.00003	0.0336	0.0001	96.175	0.0370	0.0130	0.0000		0.1302
3	0.0010	0.0610	0.0980		0.00003	0.0340	0.0003	96.267	0.0390	0.0203	0.0002		0.1400
4	0.0011	0.0620	0.0990		0.0003	0.0340	0.0003	96.370	0.0330	0.0210	0.0004		0.1400
5		0.0630	0.0995			0.0350	0.0004	96.500	0.0407	0.0223	0.0007	< 0.00005	0.1400
6		0.0630	0.1005			0.0352	0.0006	96.578	0.0428	0.0225	0.0007	<0.0001	0.1410
7		0.0630	0.1010			0.0360	< 0.00005	96.650	0.0430	0.0227	0.0007	< 0.0001	0.1450
8		0.0632	0.1015		< 0.0001	0.0366	< 0.0005	96.663	0.0430	0.0230	0.0008		0.1460
9		0.0632	0.1025		< 0.0001	0.0371	< 0.0005	96.670	0.0438	0.0234	0.0008		0.1460
10		0.0640	0.1030		< 0.0005	0.0372	< 0.001	96.710	0.0440	0.0237	0.0008		0.1480
11		0.0642	0.1030	< 0.002	< 0.001	0.0380	< 0.001	96.800	0.0455	0.0240	< 0.000	<0.002	0.1488
12		0.0648	0.1048	< 0.002	< 0.002	0.0385	< 0.001	97.250	0.0457	0.0242	< 0.0005	5 < 0.005	0.1500
13		0.0650	0.1050	< 0.002	< 0.002	0.0385	< 0.002	97.350	0.0459	0.0249	< 0.001		0.1510
14		0.0653	0.1100	< 0.005	< 0.002	0.0390	< 0.005		0.0462	0.0250	< 0.002		0.1512
15		0.0670	0.1120		< 0.005	0.0390			0.0472	0.0259	< 0.002		0.1517
16		0.0681				0.0400			0.0475	0.0276	< 0.002		
17		0.0703							0.0496	0.0276	< 0.005		
18									0.0500				
19													
20													
Mean	0.0010	0.0640	0.1020			0.0366	0.0004	96.605	0.0438	0.0235	0.0006	0.0044	0.1453
STDV	0.0002	0.0026	0.0048	0.0001	0.0008	0.0022	0.0002	0.4001	0.0039	0.0023	0.0002	0.0038	0.0049
Certified	(<0.001)	0.064	0.102	0.0002	(0.001)	0.037	0.0004	(96.6)	0.044	0.023	0.0006	(0.004)	0.145
UCRM		0.002	0.003	0.0001		0.001	0.0002		0.002				0.003
Methods	IM,O,I	O,I,IM,X	O,I,IM,X	κ IM,I,Ο,Σ	(IM,I,O,X	O,I,IM,X	O,IM,I,X	O,I,W,X	O,I,IM,X	O,I,IM,X	( IM,I,O,λ	( O,IM,I,X	O,IM,I,X
					•		•	<b>o</b> :			- 1		
4	0	P		Pb	S	Sb	Se	Si	S		Zn	Zr	
1	0.0010	0.08		0.0410	0.0009	0.0150	0.0001	0.0021	1.89		0.7080	0.0001	
2	0.0020	0.0930		0.0421	0.0011	0.0177 0.0180	0.0003	0.0032			0.7120	0.0001 0.0018	
3 4				0.0430	0.0014	0.0180	0.0007	0.0038			0.7200 0.7293	0.0018	
5	0.096			0.0430	0.0015	0.0100	0.0011	0.0040	1.99		0.7350	0.0020	
6	0.098			0.0440	0.0015	0.0190	0.0011	0.0041			0.7350	< 0.0020	
7	0.1004			0.0455	0.0010	0.0132	<0.0005	0.0044			0.7357	<0.00003	
8	0.1004			0.0456	0.0018	0.0200	<0.0005	0.0050			0.7370	<0.0005	
9	0.1020			0.0460	0.0025	0.0200	< 0.000	0.0054			0.7430	< 0.0005	
10	0.1020			0.0465	<0.0001	0.0215	< 0.001	0.0059 2.0				< 0.001	
11	0.1050			0.0470	< 0.003	0.0218		<0.002 0.0060				< 0.001	
12	0.1085			0.0470		0.0220	< 0.005	0.0064			0.7495 0.7522	< 0.001	
13	0.1100			0.0471		0.0221	< 0.005	0.0080			0.7530	< 0.002	
14	0.1110		10	0.0474		0.0222	0.0120		2.07	2.0710 0		<0.002	
15	0.1135		35	0.0480		0.0227		< 0.0005 2.08		300	0.7650	<0.002	
16	0.1150			0.0499		0.0260		<0.005 2.1		)70	0.7800	<0.005	
17	0.1170			0.0521				2		00 0.7893			
18		0.11	76						2.18	350	0.7900		
19											0.7960		
20											0.7990		
Mean	0.0015 0.1044			0.0460	0.0016	0.0204	0.0008	0.0054			0.7516	0.0012	
STDV	0.0007	0.00	84	0.0028	0.0005	0.0026	0.0005	0.0024			0.0273	0.0010	
											0 75	(0.004)	
Certified	(<0.002)	0.10		0.046	0.0016	0.020	0.0008	(0.005)			0.75	(0.001)	
		0.10 0.00 0,I,IM	)5	0.046 0.002 0,I,IM,X	0.0016 0.0003 C,O,I	0.020 0.001 0,I,IM,X	0.0008 0.0005 0,IM,I,X	(0.005) O,I,IM,X,	0.0	)4	0.75 0.01 0,I,IM,X	(0.001) O,I,IM,X	

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

